Search Notes



Application/Control No.	Applicant(s)/P Reexaminatio
10/772,435	SHIRAISHI E
Examiner	Art Unit

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SHIRAISHI ET A	AL.
Art Unit	

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John	L. God	odrow

SEARCHED			
Class	Subclass	Date	Examiner
430	108.6	8/28/2006	jG
	109.4		
	120		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
430	108.6	8/28/2006	JG
	109.4		
	120		

SEARCH NO (INCLUDING SEARCH		)
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inventor name search and east	8/28/2006	JG